

Scope of Accreditation

(Measurement Method)

Accreditation Number : VLAC-048

Expiration Date : November 28, 2020

[Name of Laboratory]

DAIKIN INDUSTRIES, LTD.

[Test site name]

Technology and Innovation Center EMC SITE

[Test site Address]

1-1, Nishi-Hitotsuya, Settsu, Osaka 566-8585

[Measurement Method]

Emission test

Radiated disturbance : Enclosure Port

Disturbance electric field test

[Test condition] On the reference ground plane, Measurement distance : 3m/10m
Measurement Frequency Range : 30 MHz - 1 GHz

[Test condition] Quasi Free Space
Measurement Frequency Range : 1 GHz - 6 GHz

Disturbance electric power measurement [Test condition] Absorption clamp (ACA)

Conducted disturbance Measurement: AC mains port

Conducted disturbance Measurement: Voltage Measurement

[Test condition] AMN, High-impedance probe

Conducted disturbance Measurement: Telecommunication port

Conducted disturbance Measurement: Voltage Measurement

[Test condition] ISN, AAN, High-impedance probe

Conducted disturbance Measurement: Current measurement

[Test condition] Current probe

Immunity test

Electro static discharge test Contact discharge, Air discharge, Indirect discharge

Radiated electromagnetic field strength Measurement Frequency Range : 80 MHz – 2.7 GHz

Electrical fast transient/burst (EFT/B) Mains port, Telecommunication/Signal port

Surge Mains port, Telecommunication/Signal port

RF conducted interference Mains port measurement frequency Range : 150 kHz - 230 MHz

Telecommunication/ Signal port measurement frequency Range : 150 kHz - 230 MHz

Radiated magnetic field

Interruptions and Voltage variations

Harmonic current

Harmonic current test, Voltage changes, Voltage fluctuations and Flicker test

Telecommunication equipment performance 2

Magnetic field strength (Magnetic probe)

Voluntary EMC Laboratory Accreditation Center Inc.

Scope of Accreditation

(Test standards)

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[Test Standards]

Emission test

**VCCI Technical Requirement : V-3/VCCI-CISPR 32, CISPR14-1, CISPR22, CISPR32
EN 55014-1, EN 55022, EN 55032, J55014-1, J55022, J55032
AS/NZS CISPR 14.1, AS/NZS CISPR 22, AS/NZS CISPR 32
AS/NZS 61000.6.3, AS/NZS 61000.6.4
IEC 61000-6-3, IEC 61000-6-4, EN 61000-6-3, EN 61000-6-4**

Immunity test

**CISPR 14-2, CISPR 24, CISPR 35, EN 55014-2, EN 55024, EN 55035
IEC 61000-4-2, IEC 61000-4-3, IEC 61000-4-4, IEC 61000-4-5, IEC 61000-4-6
IEC 61000-4-8, IEC 61000-4-11, IEC 61000-4-34, IEC 61000-6-1, IEC 61000-6-2,
EN 61000-4-2, EN 61000-4-3, EN 61000-4-4, EN 61000-4-5, EN 61000-4-6
EN 61000-4-8, EN 61000-4-11, EN 61000-4-34, EN61000-6-1, EN 61000-6-2
AS/NZS CISPR 14.2, AS/NZS CISPR 24, AS/NZS 61000.6.1, AS/NZS 61000.6.2
JIS C 61000-4-2, JIS C 61000-4-3, JIS C 61000-4-4, JIS C 61000-4-5, JIS C 61000-4-6
JIS C 61000-4-8, JIS C 61000-4-11, JIS C 61000-4-34, JIS C 61000-6-1, JIS C 61000-6-2**

Harmonic Test in Public Low Voltage Systems

**IEC 61000-3-2, IEC 61000-3-12, IEC 61000-3-3, IEC 61000-3-11, JIS C61000-3-2
IEC 61000-6-3, IEC 61000-6-4, EN 61000-6-3, EN 61000-6-4
EN 61000-3-2, EN 61000-3-12, EN 61000-3-3, EN 61000-3-11
AS/NZS 61000.3.2, AS/NZS 61000.3.12, AS/NZS 61000.3.3, AS/NZS 61000.3.11
AS/NZS 61000.6.3, AS/NZS 61000.6.4**

Telecommunication equipment performance 2

IEC 62233, EN 62233, JIS C 1912

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